

PICTURE BOOK

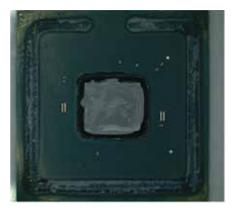
Time Domain Reflectometry (TDR)

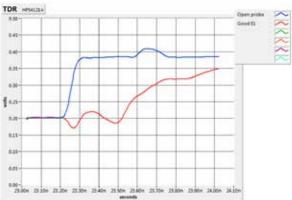
Timing measurements of reflected signals in packaged parts. Comparison to a known good part establishes deviation point of failing part. Used to identify location of failure to substrate, interconnect or die.

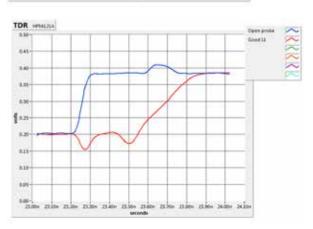
Each layer in the package may be inspected optically and probed electrically.

TDR ON BGA, TWO PINS CHECKED

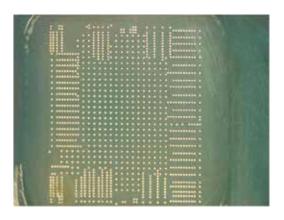
As received







Die removed



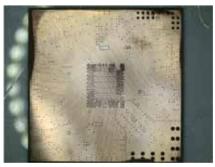


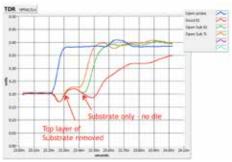


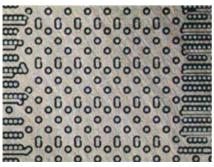
Time Domain Reflectometry (TDR)

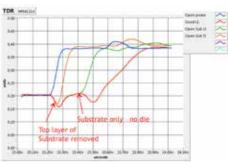
TDR ON BGA, TWO PINS CHECKED

Top layer of substrate removed









TDR ON BGA, TWO PINS CHECKED

Last layer of substrate removed

